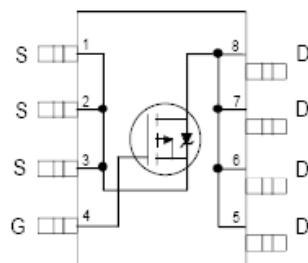
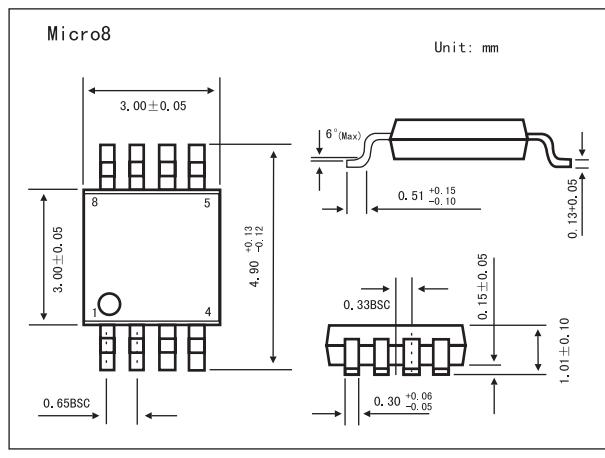


HEXFET® Power MOSFET

KRF7663

■ Features

- Trench Technology
- Ultra Low On-Resistance
- P-Channel MOSFET
- Very Small SOIC Package
- Low Profile (<1.1mm)
- Available in Tape & Reel



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{Ds}	-20	V
Continuous Drain Current, V _{GS} @ -4.5V @ T _a = 25°C	I _D	-8.2	A
Continuous Drain Current, V _{GS} @ -4.5V @ T _a = 70°C	I _D	-6.6	
Pulsed Drain Current *1	I _{DM}	-66	
Power Dissipation @ T _a = 25°C	P _D	1.8	W
Power Dissipation @ T _a = 70°C		1.15	
Linear Derating Factor		10	mW/°C
Single Pulse Avalanche Energy *2	E _{AS}	115	mJ
Gate-to-Source Voltage	V _{GS}	±12	V
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to + 150	°C
Maximum Junction-to-Ambient *3	R _{θ JA}	70	°C/W

*1 Repetitive rating; pulse width limited by max. junction temperature.

*2 Starting T_J = 25°C, L = 17.8mH, R_G = 25 Ω, I_{AS} = -3.6A

*3 When mounted on 1 inch square copper board, t<10 sec

KRF7663■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250 \mu\text{A}$	-20			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	$I_D = -1\text{mA}$, Reference to 25°C		-0.01		$\text{V}/^\circ\text{C}$
Static Drain-to-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -7.0\text{A}^*$		0.02		Ω
		$V_{\text{GS}} = -2.5\text{V}, I_D = -5.1\text{A}^*$		0.04		
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250 \mu\text{A}$	-0.60		-1.2	V
Forward Transconductance	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -7.0\text{A}^*$	14.5			S
Drain-to-Source Leakage Current	I_{DSS}	$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}$			-1.0	μA
		$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 70^\circ\text{C}$			-25	
Gate-to-Source Forward Leakage	I_{GSS}	$V_{\text{GS}} = -12\text{V}$			-100	nA
Gate-to-Source Reverse Leakage		$V_{\text{GS}} = 12\text{V}$			100	
Total Gate Charge	Q_g	$I_D = -6.0\text{A}$		30	45	nC
Gate-to-Source Charge	Q_{gs}	$V_{\text{DS}} = -10\text{V}$		5.0	7.5	
Gate-to-Drain ("Miller") Charge	Q_{gd}	$V_{\text{GS}} = -5\text{V}$		7.0	10.5	
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -10\text{V}$		11		ns
Rise Time	t_r	$I_D = -6\text{A}$		100		
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			125		
Fall Time	t_f	$R_G = 6.2 \Omega$		172		
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}$		2520		pF
Output Capacitance	C_{oss}	$V_{\text{DS}} = -10\text{V}$		615		
Reverse Transfer Capacitance	C_{rss}	$f = 1.0\text{MHz}$		375		
Continuous Source Current (Body Diode)	I_s	MOSFET symbol showing the integral reverse p-n junction diode.			-1.8	A
Pulsed Source Current (Body Diode) *2	I_{SM}				-66	
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_s = -7\text{A}, V_{\text{GS}} = 0\text{V}^*$			-1.2	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}, I_F = -2.5\text{A}$		70	105	ns
Reverse RecoveryCharge	Q_{rr}	$dI/dt = -100\text{A}/\mu\text{s}^*$		50	75	μC

*1 Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

*2 Repetitive rating; pulse width limited by max. junction temperature.

